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Substitute for form 1449A/PTO  <b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (use as many sheets as necessary)				<b>COMPLETE IF KNOWN</b>	
				Application Number	09/955,712
				Filing Date	September 19, 2001
				First Named Inventor	SHALAEV
				Group Art Unit	<del>1773</del> 2872
Examiner Name	Lavarias				
Sheet	1	of	2	Attorney Docket Number	37000-0015

**U.S. PATENT DOCUMENTS**

Examiner Initials	Cite No. <sup>1</sup>	U.S. Patent Document Number	Kind Code <sup>2</sup> (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
ku		4,448,485		Bergman, et al.	05/15/1984	
ku		4,583,818		Chen, et al.	04/22/1986	
ku		5,067,788		Jannson et al.	11/26/1991	
ku		5,113,473		Yoshida et al.	05/12/1992	
ku		5,273,617		Fathauer et al.	12/28/1993	
ku		5,472,777		Kineri et al.	12/05/1995	
ku		5,401,569		Kineri et al.	03/28/1995	

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Examiner Initials	Cite No. <sup>1</sup>	Foreign Patent Document Office <sup>3</sup>	Number <sup>4</sup>	Kind Code <sup>5</sup> (if known)	Name of Patentee of Applicant of Cited Document	Date of Publication of Cited Document	Pages, Columns, Lines Where Relevant Passages or Relevant Figures Appear	T <sup>6</sup>
					NONE			

Examiner Signature	<i>Amel C. Lavarias</i>	Date Considered	3/27/03
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4. For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. 5. Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. 6. Applicant is to place a check mark here if English language Translation is attached.

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				Group Art Unit	1773 2872
				Examiner Name	Lavarías
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AC		5,817,410		Tsujimura et al.	10/06/1998	
AC		5,858,799		Yee et al.	01/12/1999	
AC		6,017,630		Tanaka et al.	01/25/2000	
AC		6,033,774		Yitzchaik et al	03/07/2000	
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AC		6,094,413		Guerra	07/25/2000	
AC		6,115,348		Guerra	09/05/2000	
AC		6,122,091		Russell	09/19/2000	

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			NONE			

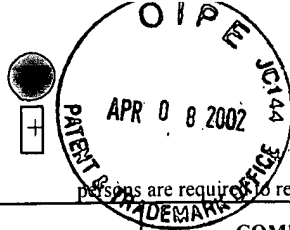
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				Application Number	09/955,712	
				Filing Date	September 19, 2001	
				First Named Inventor	Vladimir M. SHALAEV	
				Group Art Unit	4515 2872	
				Examiner Name	Lavaries	
Sheet	1	of	2	Attorney Docket Number		37000-0015

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OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS			
Examiner Initials	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	T <sup>2</sup>
Au		SHALAEV, V.M., "Nonlinear Optics of Random Media--Fractal Composites and Metal-Dielectric Films," Springer-Verlag Berlin Heidelberg, pp 1-155 (2000)	
Au	✓	SARYCHEV, A.K., et al., "Electromagnetic Field Fluctuations and Optical Nonlinearities in Metal-Dielectric Composites," Elsevier (Amsterdam - Lausanne - New York - Oxford - Shannon - Tokyo), pp 275-371, <i>Physics Reports</i> 335 (2000)	✓
Au	✓	GRESILLON S., et al., "Experimental Observation of Localized Optical Excitations in Random Metal-Dielectric Films," <i>Physical Review Letters</i> , Vol. 82, No. 22, pp 4520-4523 (May 31, 1999)	✓
Au	✓	SARYCHEV, A.K., et al., "Anderson Localization of Surface Plasmons and Nonlinear Optics of Metal Dielectric Composites," <i>Physical Review B</i> , Vol. 60, No. 24, pp 16389 - 16408 (December 16 1999 II)	✓
Au	✓	SHALAEV, V.M., et al., "Nonlinear Optics of Random Metal-Dielectric Films," <i>Physical Review B</i> , Vol. 57, No. 20, pp 13265-13287 (May 15, 1999 II)	✓
Au	✓	SARYCHEV, A.K., et al., "Percolation-Enhanced Nonlinear Scattering from Metal-Dielectric Composites," <i>Physical Review E</i> , Vol. 59, No. 6, pp 7239-7241 (June 1999)	✓
Au	✓	CHANG, R.K., et al., Editors "Optical Processes in Microcavities, World Scientific - Singapore-New Jersey-London-Hong Kong pp 1-75 (1996)	✓
Au	✓	PRAESLER, M.A., "Near-Field Optics Theory, Instrumentation, and Applications, Wiley-Interscience Publication of John Wiley & Sons, Inc., New York, pp 1-65 (1996)	✓

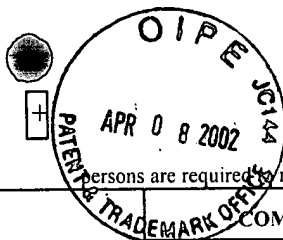
Examiner Signature	<i>Amel C. Lavaries</i>	Date Considered	3/27/03
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Application Number	09/955,712
Filing Date	September 19, 2001
First Named Inventor	Vladimir M. SHALAEV
Group Art Unit	1545 2872
Examiner Name	Lavarias
Attorney Docket Number	37000-0015

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## OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS

Examiner Initials	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	T <sup>2</sup>
AC	✓	CRANE, R., et al., Editors, "Materials for Optical Limiting," <i>Materials Research Society Symposium Proceedings</i> , Vol. 374, Table of Contents (November 28, 1994)	✓
AC	✓	HOOD, P., et al., Editors, "Materials for Optical Limiting II," <i>Materials Research Society Symposium Proceedings</i> , Vol. 479, Table of Contents (March 31, 1997)	✓
AC	✓	TURRO, N.J., "Modern Molecular Photochemistry, <i>University Science Books, Columbia University</i> , Sausalito, Californiam Chapter11.1 - 1.10 (1991)	✓
AC	✓	SERPONE, N., "Photocatalysis - Fundamentals and Applications," J. Wiley & Sons, Wiley Interscience Publication, New York Chapters 1 and 7 (1989)	✓
AC	✓	KOHEN, E., et al., "PhotoBiology," Academic Press, San Diego, New York, Boston, London, Sydney, Tokyo Toronto, 4-6 and 9 (1995)	✓
AC	✓	PETRANOVSKII, V., et al., "Plasmon Resonance of Copper Nanoparticles Within Zeolites: The Effect of Matrix Composition and Agglomeration Temperature," <i>Proc of SPIE</i> , Vol. 4467 (2001)	✓

Examiner Signature	<i>Amel C Lavarias</i>	Date Considered	3/27/03
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ku	✓	GORNIK, E., "Geometrical Shaping of Microlaser Emission Patterns," <i>Science</i> , Vol. 280, pp 1544-1545 (June 5, 1998)	
ku	✓	NÖCKEL, J.U., et al., "Chaotic Light: A Theory of Asymmetric Resonant Cavities," <i>Optical Processes in Microcavities</i> , edited by R.K. Chang and A.J. Campillo (World Scientific Publishers (1996),	

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Examiner Signature	<i>Ann C. Lavarias</i>	Date Considered	3/24/03
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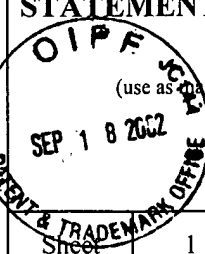
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			First Named Inventor	V.M. SHALAEV, et al.
			Group Art Unit	<del>1773</del> 2872
			Examiner Name	Lavarlas
Sheet 1	of 2	Attorney Docket Number	37000-0015	

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ku		5,527,712	A	T.M. Sheeny	06/18/1996	

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		Office <sup>3</sup>	Number <sup>4</sup>	Kind Code <sup>5</sup> (if known)				
					NONE			

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HL	✓	DUCOURTIEUX, S., et al., "Percolation and Fractal Composites: Optical Studies," <i>J of Nonlinear Optical Physics &amp; Materials</i> , Vol. 9, No. 1, pp 105-116 (2000)	
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